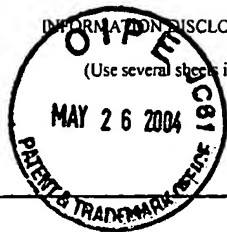


INFORMATION DISCLOSURE CITATION

(Use several sheets if necessary)



Docket Number (Optional) FUJI:200A)

SERIAL NO.: 10/646,590

APPLICANT(s) Takashi KOBAYASHI et al.

FILING DATE: August 22, 2003

Group Art Unit 2826

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
VAMS	US	4,602,266 A	7/86	Coe	357	20	
VAMS	US	5,345,101 A	6/94	Tu	257	495	

FOREIGN PATENT DOCUMENTS

	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
VAMS	GB	1427014 A	3/76	GB				

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER	DATE CONSIDERED		
<i>[Signature]</i>	9-1-04		

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

INFORMATION DISCLOSURE CITATION

(Use several sheets if necessary)

Docket Number (Optional)

FUJI: 200A

Application Number

10/646,590

Applicant(s)

Takashi KOBAYASHI et al.

Filing Date

August 22, 2003

Group Art Unit

2811

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
VAMS	US 4,412,242	10/83	Herman et al.	357	52	
	US 4,399,449	8/83	Herman et al.	357	53	
	US 5,338,961	8/94	Lidow et al.	257	342	
	US 6,476,456	11/02	Boden, Jr.	257	486	
	US 6,114,726	9/00	Barkhordarian	257	341	
	US 4,809,045	2/89	Yilmaz	357	23.4	
	US 5,028,548	7/91	Nguyen	437	15	
	US 5,510,634	4/96	Okabe et al.	257	139	

FOREIGN PATENT DOCUMENTS

REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						YES	NO
VAMS	EP 0 671 769 A2	9/95	EPO				
	EP 0 749 163 A2	12/96	EPO				
	EP 0 115 093 A2	8/84	EPO				
	GB 2 161 649 A	1/86	GB				

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

VAMS	"Optimization and Surface Charge Sensitivity of High-Voltage Blocking Structures with Shallow Junctions"; Hamza Yilmaz; July 1991; IEEE Transactions on Electron Devices, Vol. 38, No. 7; pages 1666-1675.
VAMS	"A Parametric Study of Power Mosfets"; Chenming Hu; Proceedings of the Conference of Rec. Power Electronics Specialists, 1979 IEEE; pages 385-395.

EXAMINER	Victor A. Mandala	DATE CONSIDERED	9-1-04
----------	-------------------	-----------------	--------

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.